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IP4-A4: Lab tour ”ProVIS Tour 2: Electron microscopy at ProVIS”

High-resolution microscopes provide insight into the structure of microscopic objects. At ProVIS the scanning electron- and helium-ion microscopes are embedded in the correlative workflows alongside with microanalytical techniques, such as SIMS. During the tour the participants will learn about applications in (environmental-)microbiology, the basic principles of the microscopes, sample preparation techniques as well as image registration of correlative microscopy data. It is planned to give participants the opportunity to operate the scanning electron microscope.

Primary authors: SCHMIDT, Matthias; MUSAT, Niculina

Presenters: SCHMIDT, Matthias; MUSAT, Niculina

Session Classification: Breakout Session